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Abbreviations

2ME	2-methoxyethanol
BLSF(s)	Bismuth layer-structured ferroelectric(s)
CSD	Chemical solution deposition
EBDW	Electron beam direct writing
EFM	Electrostatic force microscopy
FeRAM	Ferroelectric random access memory
PZT	$\text{Pb}(\text{Zr}_x\text{Ti}_{1-x})\text{O}_3$
PLD	Pulsed laser deposition
RAM	Random access memory
STO	SrTiO_3
SBT	$\text{SrBi}_2\text{Ta}_2\text{O}_9$
SEM	Scanning electron microscopy
SFM	Scanning force microscopy
SPM	Scanning probe microscopy
TEM	Transmission electron microscopy
XRD	X-ray diffraction
YSZ	Yttria-stabilized zirconia